

# UNISONIC TECHNOLOGIES CO., LTD

UTT30N08 Preliminary Power MOSFET

# 80V, 30A N-CHANNEL POWER MOSFET

#### **■** DESCRIPTION

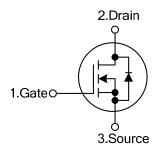
The UTC **UTT30N08** is an N-channel mode power MOSFET using UTC's advanced technology to provide customers with planar stripe and DMOS technology. This technology allows a minimum on-state resistance and superior switching performance. It also can withstand high energy pulse in the avalanche and commutation mode.

The UTC  ${\bf UTT30N08}$  is generally applied in high efficiency switch mode power supplies.



- \*  $R_{DS(ON)}$ <40m $\Omega$  @  $V_{GS}$ =10V,  $I_D$ =30A
- \* Low Gate Charge (Typical 48nC)
- \* Low C<sub>RSS</sub> (Typical 30pF)
- \* High Switching Speed

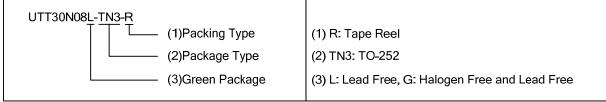
#### ■ SYMBOL



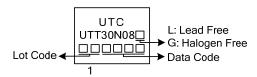
#### ORDERING INFORMATION

Ordering Number		Darling	Pin Assignment			Daaldaa	
Lead Free	Halogen Free	Package	1	2	3	Packing	
UTT30N08L-TN3-R	UTT30N08G-TN3-R	TO-252	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



#### ■ MARKING



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TO-252

# ■ **ABSOLUTE MAXIMUM RATINGS** (T<sub>C</sub>=25°C, unless otherwise specified) (Note 4)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain to Source Voltage		$V_{DSS}$	80	V
Gate-Source Voltage		$V_{GSS}$	±20	V
Drain Current (Note 5)	T <sub>C</sub> =25°C	I <sub>D</sub>	30	Α
	Continuous $T_C=100^{\circ}C$		21.3	Α
	Pulsed (Note 2)	$I_{DM}$	120	Α
Avalanche Energy	Single Pulsed (Note 3)	E <sub>AS</sub>	300	mJ
	Repetitive (Note 2)	E <sub>AR</sub>	8	mJ
Power Dissipation (T <sub>C</sub> =25°C)		$P_D$	28	W
Junction Temperature		TJ	+150	°C
Storage Temperature		T <sub>STG</sub>	-55~+150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating; Pulse width limited by maximum junction temperature.
- 3. L=4mH,  $I_{AS}$ =30A.  $V_{DD}$ =50V,  $R_{G}$ =25 $\Omega$ , Starting  $T_{J}$ =25 $^{\circ}$ C
- 4. Drain current limited by maximum junction temperature

#### **■ THERMAL DATA**

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	$\theta_{JA}$	110	°C/W	
Junction to Case	$\theta_{JC}$	4.53	°C/W	

# **■ ELECTRICAL CHARACTERISTICS**

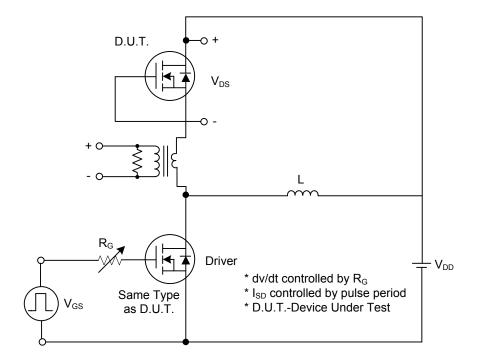
PARAMETER		SYMBOL	TEST CONDITIONS		TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		$BV_{DSS}$	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C	80			V
Drain-Source Leakage Current		$I_{DSS}$	V <sub>DS</sub> =80V, V <sub>GS</sub> =0V,			1	μΑ
Gate- Source Leakage Current	Forward	1000	V <sub>GS</sub> =+20V, V <sub>DS</sub> =0V			+100	nΑ
	Reverse		V <sub>GS</sub> =-20V , V <sub>DS</sub> =0V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{GS}=V_{DS}$ , $I_D=250\mu A$			4.0	V
Static Drain-Source On-State Resistance		R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =30A		32	40	mΩ
DYNAMIC PARAMETERS							
Input Capacitance		$C_{ISS}$			2400		pF
Output Capacitance Reverse Transfer Capacitance		Coss	V <sub>DS</sub> =25, V <sub>GS</sub> =0V, f=1.0MHz		390		pF
		$C_{RSS}$			30		pF
SWITCHING PARAMETERS							
Total Gate Charge		$Q_G$	\\ -60\\ \\ -10\\   -20\		48	60	nC
Gate to Source Charge		$Q_GS$	V <sub>DS</sub> =60V, V <sub>GS</sub> =10V, I <sub>D</sub> =30A (Note 1, 2)		15		nC
Gate to Drain ("Miller") Charge		$Q_GD$			20		nC
Turn-ON Delay Time		$t_{D(ON)}$			45		ns
Rise Time		$t_R$	$V_{DD}$ =30V, $I_{D}$ =15A, $R_{G}$ =4.7 $\Omega$		60		ns
Turn-OFF Delay Time		t <sub>D(OFF)</sub>	(Note 1, 2)		115		ns
-all-Time		$t_{F}$			66		ns
SOURCE- DRAIN DIODE RATIN	IGS AND C	HARACTERIS	TICS				
Maximum Body-Diode Continuous Current		I <sub>S</sub>				30	Α
Maximum Body-Diode Pulsed Current		I <sub>SM</sub>				120	Α
Drain-Source Diode Forward Voltage		$V_{SD}$	I <sub>SD</sub> =30A, V <sub>GS</sub> =0V			1.4	V

Notes: 1. Pulse Test: Pulse width≤300µs; Duty Cycle≤2%.

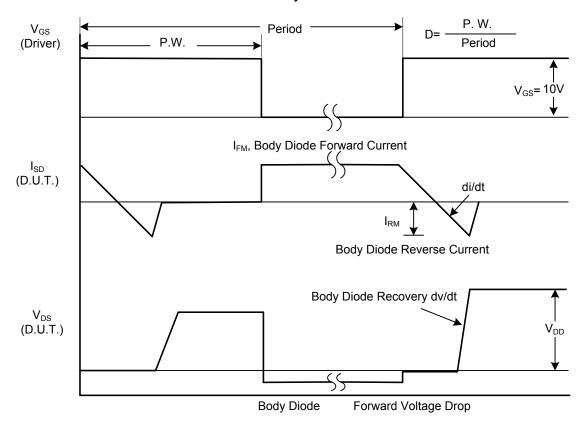
2. Essentially Independent of Operating Temperature Typical Characteristics



# ■ TEST CIRCUITS AND WAVEFORMS

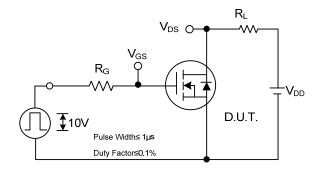


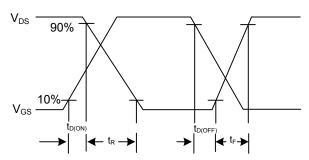
# Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

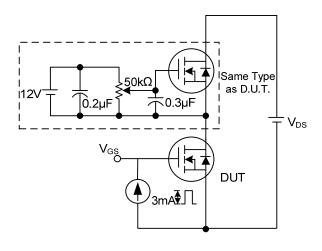
# ■ TEST CIRCUITS AND WAVEFORMS (Cont.)

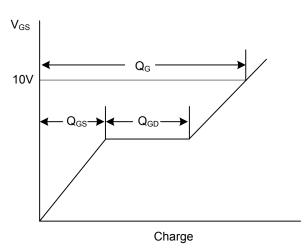




**Switching Test Circuit** 

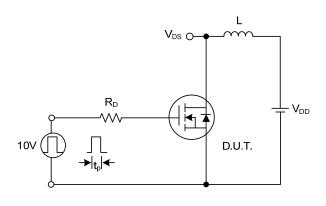
**Switching Waveforms** 

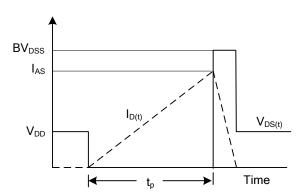




**Gate Charge Test Circuit** 

**Gate Charge Waveform** 





**Unclamped Inductive Switching Test Circuit** 

**Unclamped Inductive Switching Waveforms** 

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